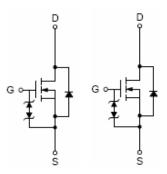
: :

# Features

- $V_{DSS}=100V/V_{GSS}=\pm 20V/I_{D}=3.5A$
- $R_{RS(ON)} = 105 \text{m}\Omega(\text{Max.}) @V_{GS} = 10V$
- .  $R_{DS(ON)} = 1.75 m \Omega(Max.) @V_{GS} = 4.5 V$
- ESD protect
- Reliable and Rugged
- High Density Cell Design For Ultra Low On-Resistance

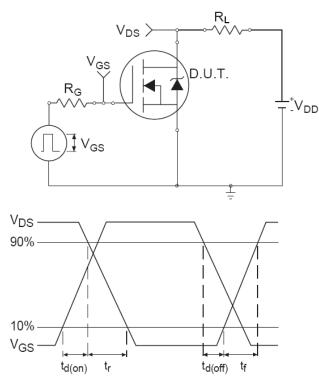
# **Pin Description**



# . Applications

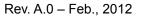
- •• "Synchronous Rectification
- Power Management in Inverter System

# Switching Time Test Circuit and Waveforms



### Package Marking and Ordering Information

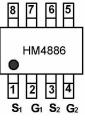
Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM4886	HM4886E	SOP-8	-	-	-







Marking and pin Assignment





SOP-8 top view

#### Parameter Symbol Typical Unit V<sub>DSS</sub> Drain-Source Voltage 100 V Gate -Source Voltage ±20 V V<sub>GSS</sub> $T_C = 70^{\circ}C$ 2.8 A $I_D^{-1}$ Continuous Drain Current 3.5 А 300us Pulsed Drain Current Tested $T_C=25^{\circ}C$ 14 A I<sub>DM</sub><sup>1</sup> $I_{S}^{1}$ **Diode Continuous Forward Current** 3 A Avalanche Energy, Single Plused(L=0.3mH) $E_{AS}^2$ 30 mJ °C **Operating Junction Temperature** 150 $T_J$ Storage Temperature Range $-55 \sim 150$ °C T<sub>STG</sub>

#### **Absolute Maximum Ratings** (T<sub>A</sub>=25°C unless otherwise noted)

Note: 1: Surface Mounted on  $1in^2$  pad area,  $t \leq 10$ sec..

2: UIS tested and pluse width limited by maximum junction temperature  $150^{\circ}$ C (initial temperature T<sub>J</sub>= $25^{\circ}$ C).

#### **Electrical Characteristics** (TA=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур	Max.	Unit
Static Char	acteristics					
<b>BV</b> <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V,I <sub>D</sub> =250uA	100			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-80V,V <sub>GS</sub> =0V			1	uA
	Zero Gate voltage Drain Current	T <sub>J</sub> =85°C			30	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =-250uA	1.5	2	2.5	V
I <sub>GSS</sub>	Gate Leakage Current	$V_{GS}$ =±16V, $V_{DS}$ =0V			±10	nA
$R_{DS(on)}^{1}$	Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =3.5A		85	105	mΩ
	Drain-Source On-Resistance	V <sub>GS</sub> =4.5V, I <sub>D</sub> =2A		135	175	
Diode Chai	racteristics					
$V_{SD}^{1}$	Diode Forward Voltage	$I_{SD}=3A, V_{GS}=0V$	0.6	0.8	1.1	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> =3.5A,		44		ns
Qrr	Reverse Recovery Charge	dI <sub>SD</sub> /dt=100A/us		80		nC
Dynamic C	haracteristics <sup>2</sup>					
C <sub>iss</sub>	Input Capacitance	V = 0 V V = 20 V		940		pF
C <sub>oss</sub>	Output Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V Frequency=1MHz		80		
C <sub>rss</sub>	Reverse Transfer Capacitance	riequency-invitiz		50		
t <sub>d(on)</sub>	Turn-On Delay Time	V = 20 V D = 200		13	24	- ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD}$ =30V, $R_L$ =30 $\Omega$ $I_D$ =1A, $V_{GEN}$ =10V		10	19	
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{G}=6\Omega$		32	60	
t <sub>f</sub>	Turn-Off Fall Time	NG-022		16	30	
Gate Charg	ge Characteristics <sup>2</sup>					
Qg	Total Gate Charge	V = 50 V V = 10 V		21		nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{DS}$ =50V, $V_{GS}$ =10V $I_D$ =3.5A		4.9		
Q <sub>gd</sub>	Gate-Drain Charge	1D-3.3A		5.8		

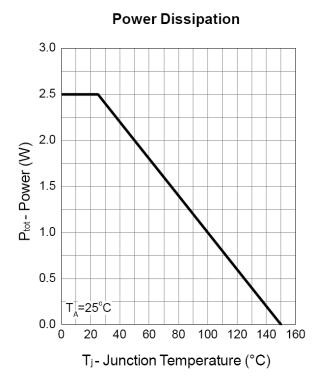
Note: 1: Pulse test ; pulse width  $\leq$  300ns, duty cycle  $\leq$  2%.

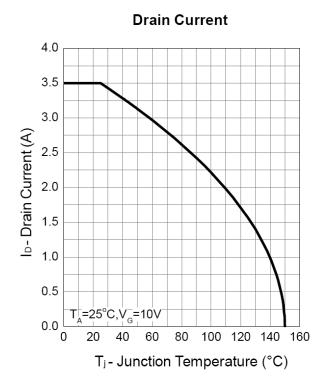
2: Guaranteed by design, not subject to production testing.

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HM4886E 100V<sub>DS</sub>/±20V<sub>GS</sub>/3.5A(I<sub>D</sub>) Dual N-Channel Enha ncement Mode MOSFET

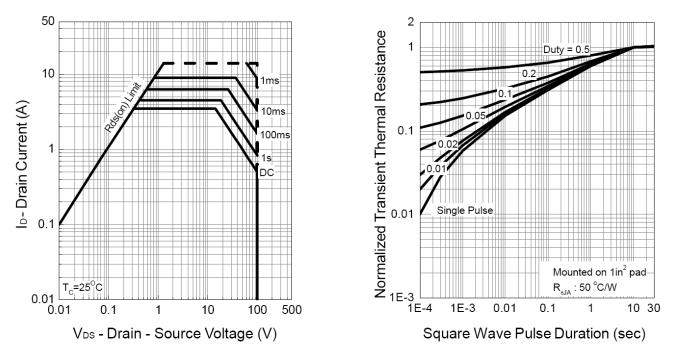
# **Typical Characteristics**





Safe Operation Area

**Thermal Transient Impedance** 

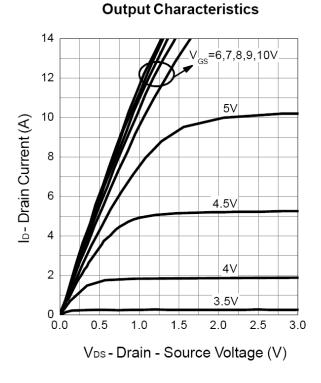


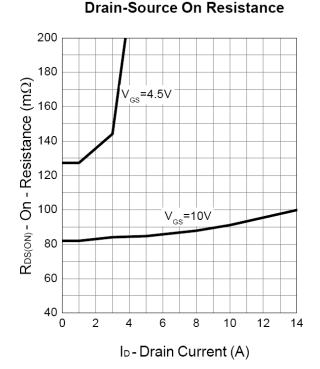
Rev. A.0 - Feb., 2012

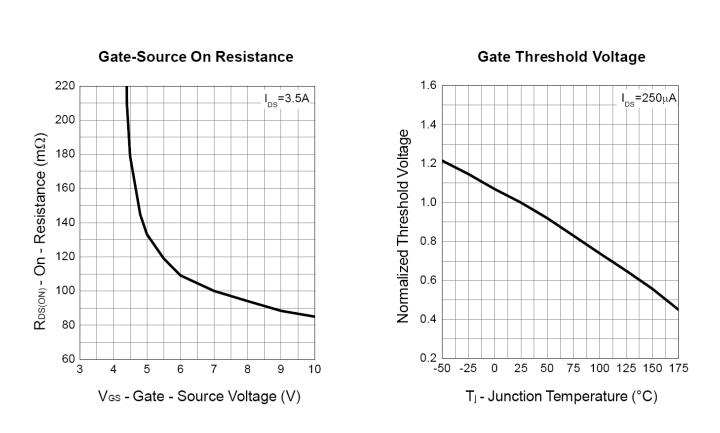
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HM4886E 100V<sub>DS</sub>/±20V<sub>GS</sub>/3.5A(I<sub>D</sub>) Dual N-Channel Enha ncement Mode MOSFET

# **Typical Characteristics (Cont.)**





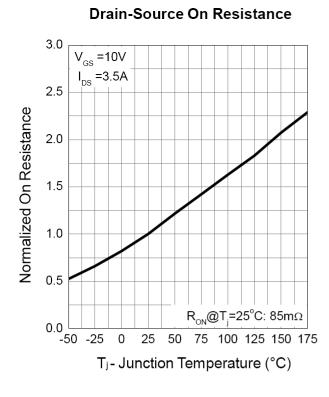


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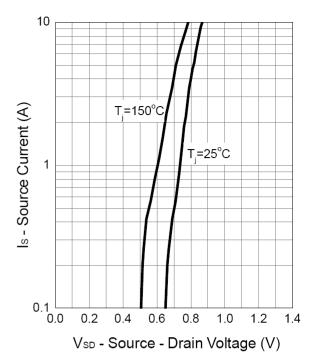
HM4886E 100V<sub>DS</sub>/±20V<sub>GS</sub>/3.5A(I<sub>D</sub>) Dual N-Channel Enha ncement Mode MOSFET

# **Typical Characteristics (Cont.)**

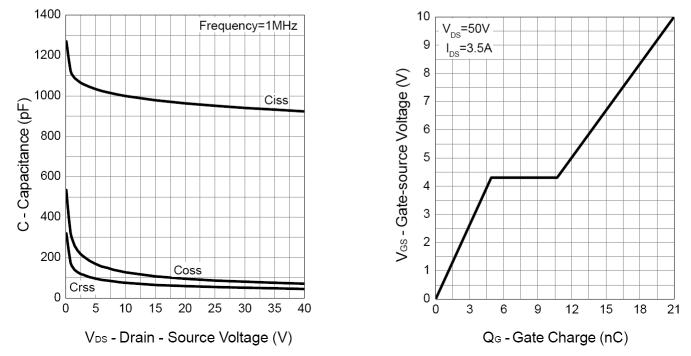


Capacitance

#### Source-Drain Diode Forward

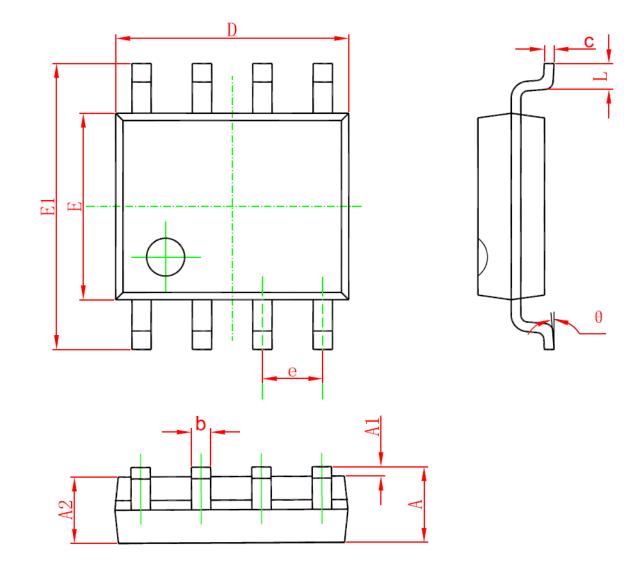






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Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
А	1.350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0.004	0.010	
A2	1.350	1.550	0.053	0. 061	
b	0. 330	0. 510	0.013	0. 020	
с	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
E	3.800	4.000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1.270	0.016	0. 050	
θ	0°	8°	0°	8°	

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